



# FQB8N60CF 600V N-Channel MOSFET

## **Features**

- 6.26A, 600V,  $R_{DS(on)} = 1.5 \Omega @V_{GS} = 10 V$
- Low gate charge (typical 28nC)
- Low Crss (typical 12pF)
- · Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability
- · RoHS Compliant

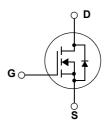


## **Description**

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switched mode power supplies, electronic lamp ballasts based on half bridge topology.





# **Absolute Maximum Ratings**

Symbol	Parameter			FQB8N60CF	Units	
$V_{\rm DSS}$	Drain-Source Vo	Drain-Source Voltage			V	
$I_{D}$	Drain Current	- Continuous (T <sub>C</sub> = 25°C)		6.26	Α	
		- Continuous (T <sub>C</sub> = 100°C)		3.96	Α	
$I_{DM}$	Drain Current	- Pulsed	(Note 1)	25	Α	
$V_{GSS}$	Gate-Source Voltage		$\pm30$	V		
E <sub>AS</sub>	Single Pulsed Avalanche Energy		(Note 2)	160	mJ	
$I_{AR}$	Avalanche Current		(Note 1)	6.26	Α	
$E_AR$	Repetitive Avalanche Energy		(Note 1)	14.7	mJ	
dv/dt	Peak Diode Recovery dv/dt (Note 3)		(Note 3)	4.5	V/ns	
P <sub>D</sub>	Power Dissipation ( $T_C = 25^{\circ}C$ ) 147 W				W	
	- Derate above 25°C			1.18	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range			-55 to +150	°C	
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8					

## **Thermal Characteristics**

Symbol	Parameter	FQB8N60CF	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.85	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient*	40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	°C/W

<sup>\*</sup> When mounted on the minimum pad size recommended (PCB Mount)

# **Package Marking and Ordering Information**

<b>Device Marking</b>	Device	Package	Reel Size	Tape Width	Quantity
FQB8N60CF	FQB8N60CFTM	D2-PAK	330mm	24mm	800

# **Electrical Characteristics** $T_C = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Charac	teristics			ı		
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	600			V
$\Delta BV_{DSS}/$ $\Delta T_J$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C		0.7		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0 V			10	μА
		V <sub>DS</sub> = 480 V, T <sub>C</sub> = 125°C			100	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Charact	teristics				•	•
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance $V_{GS} = 10 \text{ V}, I_D = 3.13 \text{A}$			1.25	1.5	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 3.13 A (Note 4)		8.7		S
Dynamic Cl	haracteristics					
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V,		965	1255	pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		105	135	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			12	16	pF
Switching C	Characteristics				•	•
t <sub>d(on)</sub>	Turn-On Delay Time $V_{DD} = 300 \text{ V}, I_D = 6.26 \text{A},$			16.5	45	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		60.5	130	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			81	170	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)		64.5	140	ns
Qg	Total Gate Charge	V <sub>DS</sub> = 480 V, I <sub>D</sub> = 6.26A,		28	36	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V		4.5		nC
Q <sub>gd</sub>	Gate-Drain Charge	e-Drain Charge (Note 4, 5)		12		nC
Drain-Source	ce Diode Characteristics and Maximum Ratings	3				
I <sub>S</sub> Maximum Continuous Drain-Source Diode For		rward Current			6.26	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward	d Current			25	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 6.26 A			1.4	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 6.26 A,		82		ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		242		nC

#### NOTES

<sup>1.</sup> Repetitive Rating : Pulse width limited by maximum junction temperature

<sup>2.</sup> L = 7.3mH, I $_{AS}$  = 6.26A, V $_{DD}$  = 50V, R $_{G}$  = 25  $\Omega$ , Starting T $_{J}$  = 25°C

<sup>3.</sup> I  $_{SD} \leq$  6.26A, di/dt  $\leq$  200A/ $\mu$ s, V  $_{DD} \leq$  BV  $_{DSS,}$  Starting T  $_{J}$  = 25°C

<sup>4.</sup> Pulse Test : Pulse width  $\leq 300 \mu s$ , Duty cycle  $\leq 2\%$ 

<sup>5.</sup> Essentially independent of operating temperature

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

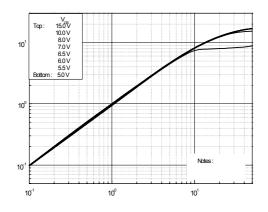


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

Figure 2. Transfer Characteristics

Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

Figure 5. Capacitance Characteristics

**Figure 6. Gate Charge Characteristics** 

# **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

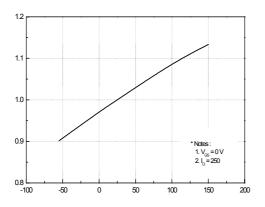


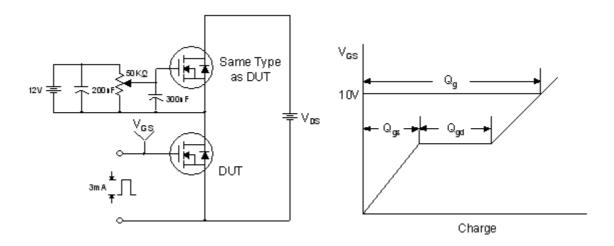
Figure 8. On-Resistance Variation vs. Temperature

Figure 9. Maximum Safe Operating Area

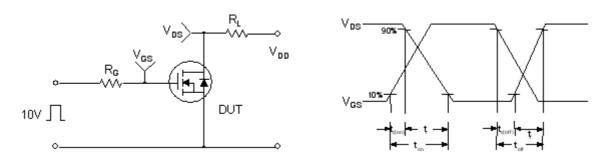
Figure 10. Maximum Drain Current vs. Case Temperature

Figure 11. Transient Thermal Response Curve

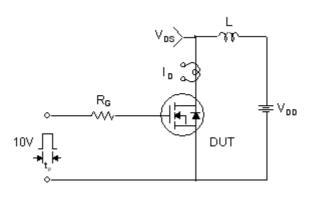
## **Gate Charge Test Circuit & Waveform**

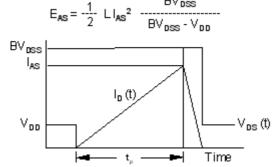


### **Resistive Switching Test Circuit & Waveforms**

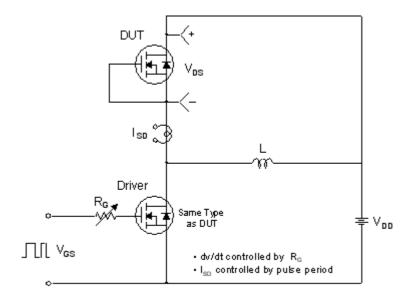


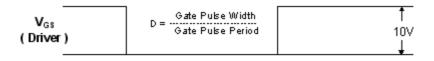
### **Unclamped Inductive Switching Test Circuit & Waveforms**

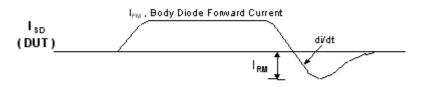


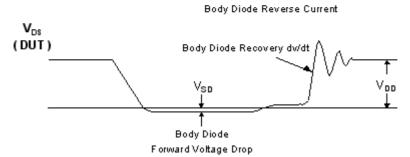


## Peak Diode Recovery dv/dt Test Circuit & Waveforms



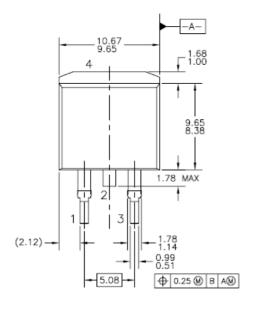


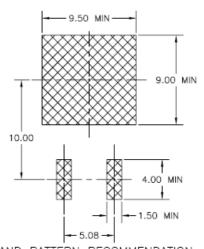




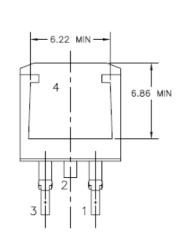
## **Mechanical Dimensions**

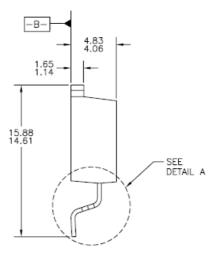
# D<sup>2</sup> - PAK

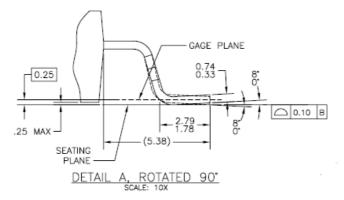




LAND PATTERN RECOMMENDATION







Dimensions in Millimeters





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